

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
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	C	US-6,232,035 B1	05-2001	Hirotsune et al.	430/270.13
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	N	WO 02017304 A2	02-2002	WIPO	Fargeix et al	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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